

## N Channel MOSFET



Lead Free Package and Finish

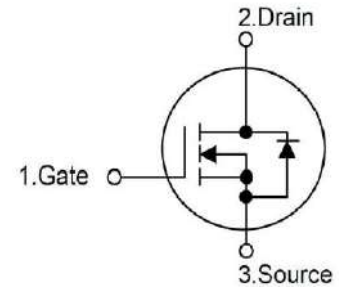
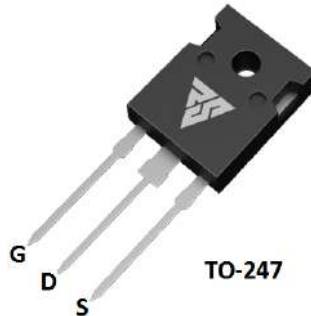
### Applications:

- Adapter & Charger
- DC-AC inverter Power
- AC-DC Switching Power Supply
- LED driving power

$I_D$	$R_{DS(ON)}(Typ.)$	$V_{DSS}$
20A	0.23Ω	500V

### Features:

- Low On Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- RoHS Compliant



### Ordering Information

Part Number	Package	Marking
RS20N50W	TO-247	RS20N50W

Not to Scale

### Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RS20N50W	Units
$V_{DSS}$	Drain-to-Source Voltage (Note*1)	500	V
$I_D$	Continuous Drain Current	20.0	A
$I_{D@ 100^\circ\text{C}}$	Continuous Drain Current	12.6	
$I_{DM}$	Pulsed Drain Current (Note*2)	80	
PD	Power Dissipation	230	W
	Derating Factor above $25^\circ\text{C}$	1.85	W/ $^\circ\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
EAS	Single Pulse Avalanche Energy $L=10\text{mH}$ $V_{DD}=50\text{V}$ $R_G=25\Omega$ $T_J=25^\circ\text{C}$	1200	mJ
TL TPKG	Maximum Temperature for Soldering	300 260	$^\circ\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds		
	Package Body for 10 seconds		
$T_J$ and $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to 150	

\*Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

### Thermal Resistance

Symbol	Parameter	RS20N50W	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	0.54	$^\circ\text{C}/\text{W}$	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of $+150^\circ\text{C}$ .
$R_{\theta JA}$	Junction-to-Ambient	62.5		1 cubic foot chamber, free air.

### OFF Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$BV_{DSS}$	Drain-to-source Breakdown Voltage	500	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	1.0	$\mu A$	$V_{DS}=500V, V_{GS}=0V$
$I_{GSS}$	Gate-to-Source Forward Leakage	--	--	100	$\mu A$	$V_{GS}=+30V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

### ON Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	--	0.23	0.28	$\Omega$	$V_{GS}=10V, I_D=10A$
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$

### Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$t_d(ON)$	Turn-on Delay Time	--	33	--	nS	$V_{DS}=250V$ $I_D=20A$ $R_G=20\Omega$
$t_{rise}$	Rise Time	--	75	--		
$t_d(OFF)$	Turn-OFF Delay Time	--	91	--		
$t_{fall}$	Fall Time	--	83	--		

### Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$C_{iss}$	Input Capacitance	--	1920	--	pF	$V_{GS}=0V$ $V_{DS}=25V$ $f=1.0MHz$
$C_{oss}$	Output Capacitance	--	290	--		
$C_{rss}$	Reverse Transfer Capacitance	--	18	--		
$Q_g$	Total Gate Charge	--	56	--	nC	$V_{DS}=400V$ $I_D=20A$ $V_{GS}=10V$
$Q_{gs}$	Gate-to-Source Charge	--	13	--		
$Q_{gd}$	Gate-to-Drain("Miller") Charge	--	20	--		

## Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I <sub>S</sub>	Continuous Source Current	--	--	20	A	Integral pn-diode in MOSFET
I <sub>SM</sub>	Maximum Pulsed Current	--	--	80	A	
V <sub>SD</sub>	Diode Forward Voltage	--	--	1.2	V	I <sub>S</sub> =20A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	--	536	--	nS	V <sub>GS</sub> =0V I <sub>S</sub> =20A, di/dt=100A/μs
Q <sub>rr</sub>	Reverse Recovery Charge	--	5.6	--	μC	

## Notes:

\*1.Repetitive rating;pulse width limited by maximum junction temperature.

## Typical Feature curve

Figure1 Typical Output Characteristics

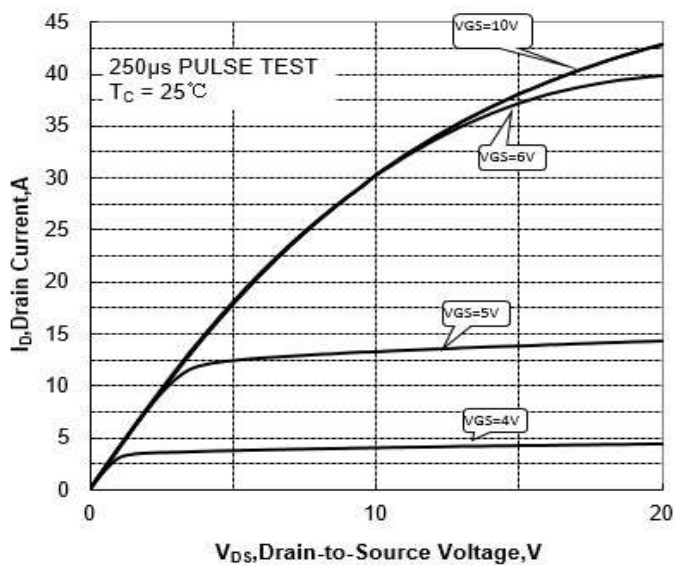


Figure2 Typical Transfer Characteristics

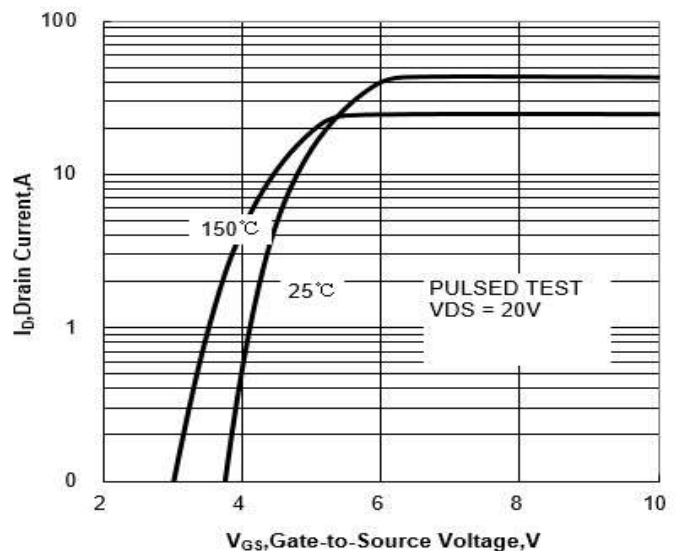


Figure3 Typical Drain to Source ON Resistance vs Drain Current

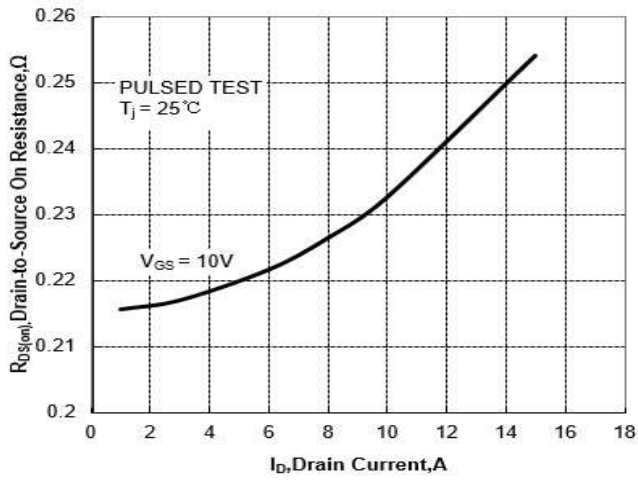


Figure4 Typical Drain to Source on Resistance vs Junction Temperature

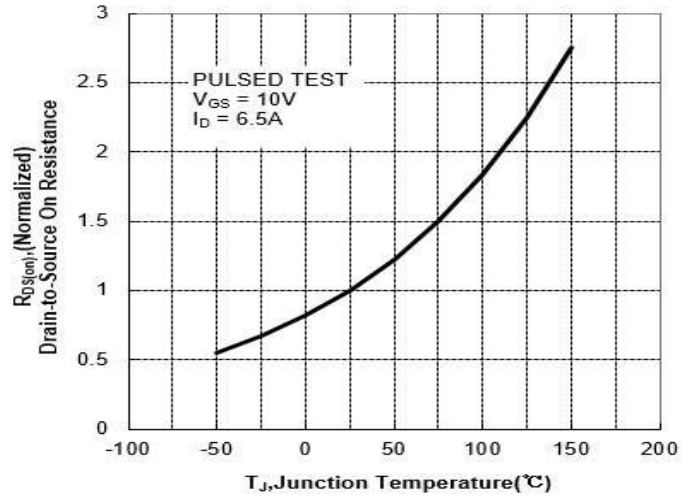


Figure5 Typical Threshold Voltage vs Junction Temperature

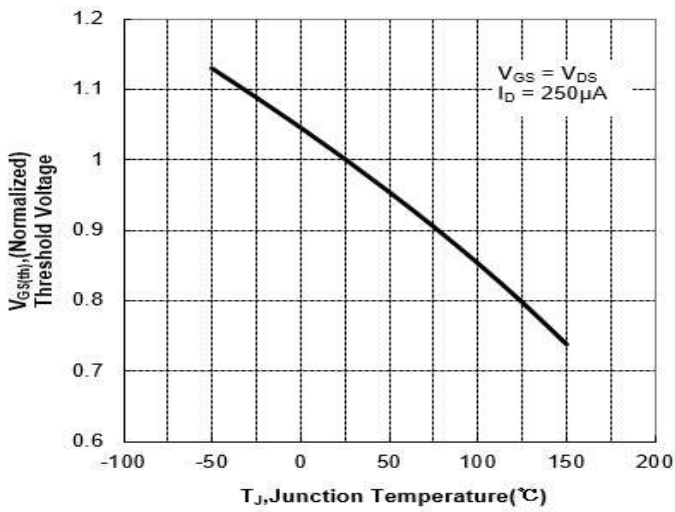


Figure6 Typical Breakdown Voltage vs Junction Temperature

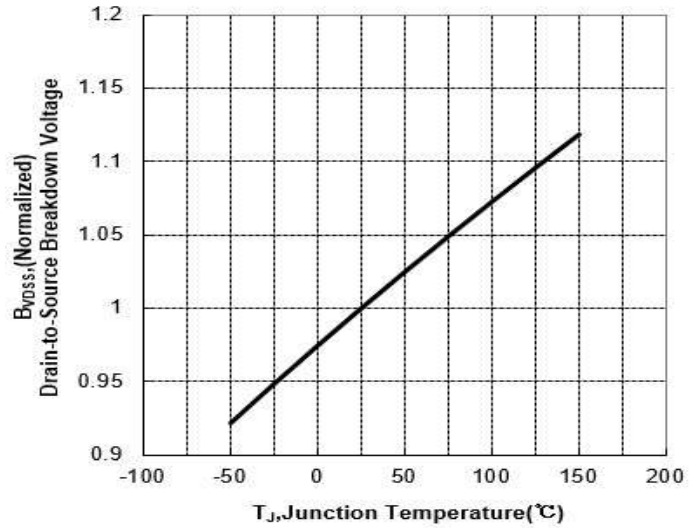


Figure7 Power Dissipation

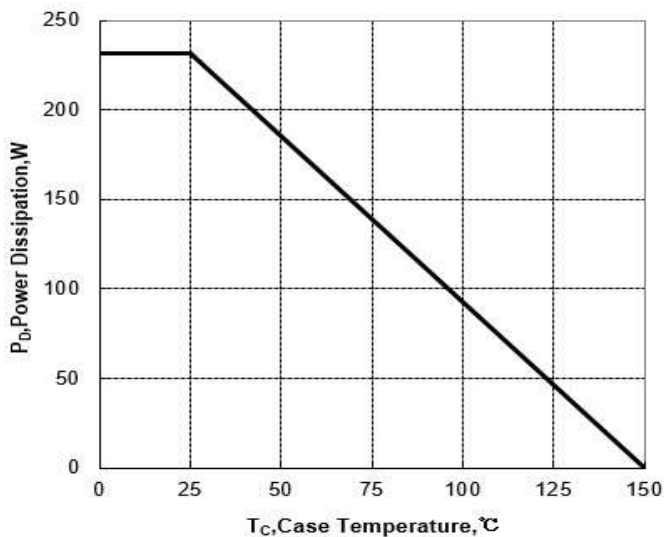


Figure8 Typical Breakdown Voltage vs Junction Temperature

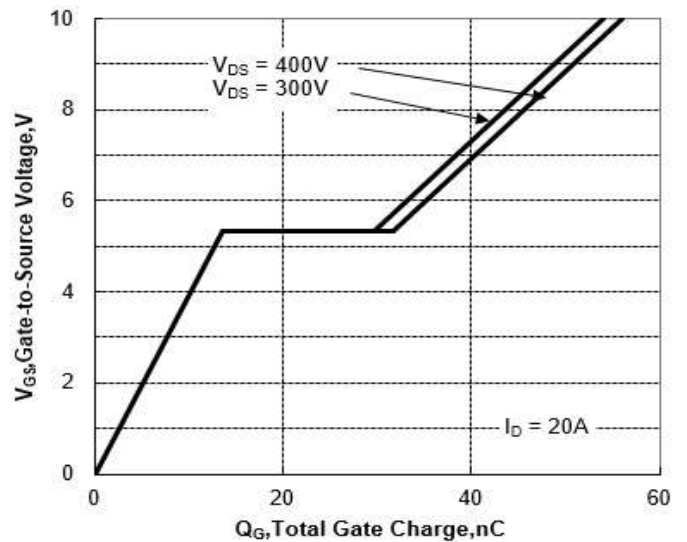


Figure9 Typical Theshold Voltage vs Junction Temperature

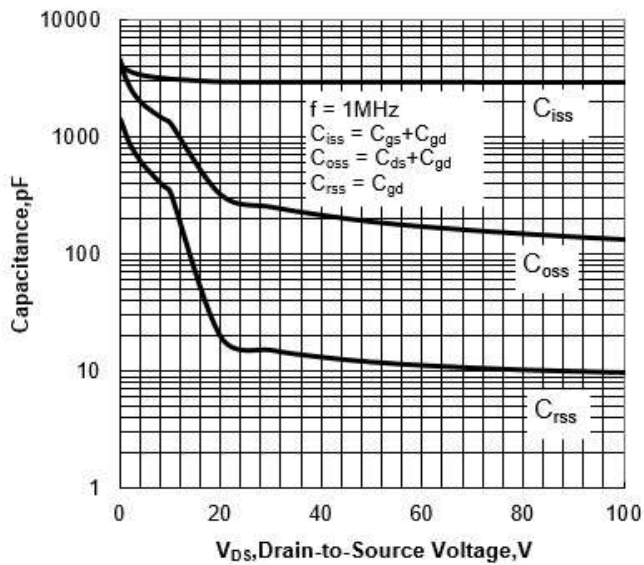


Figure10 Safe Operating Area

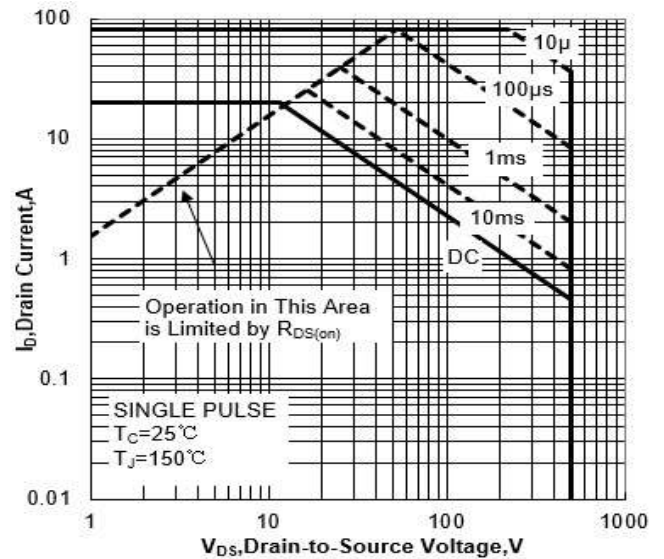
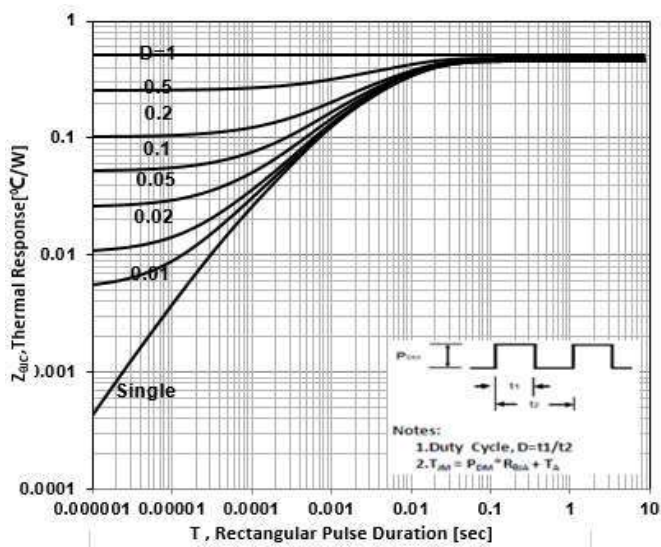


Figure11 Max Thermal Impedance



## Test Circuits and Waveforms

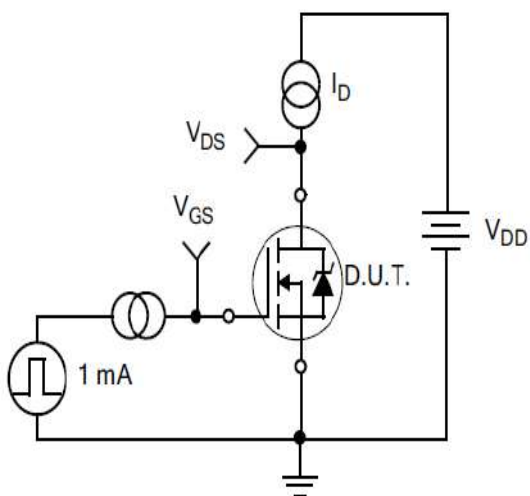


Figure12.  
Gate Charge Test Circuit

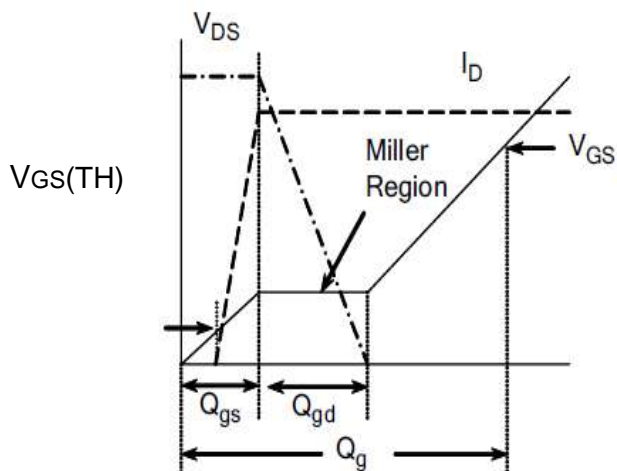


Figure13.  
Gate Charge Waveform

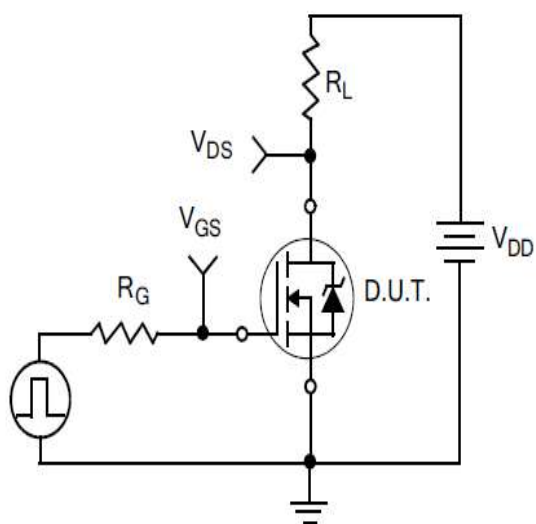


Figure14.  
Resistive Switching Test Circuit

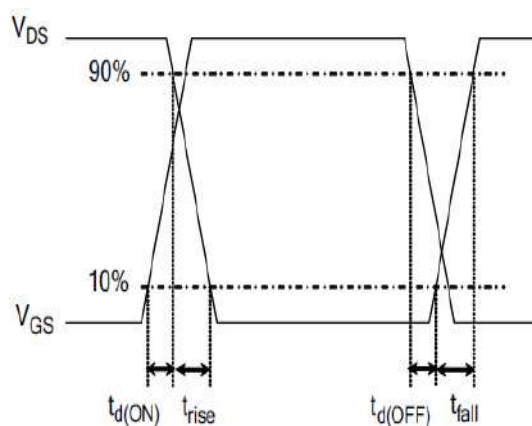


Figure15.  
Resistive Switching Waveforms

## Test Circuits and Waveforms

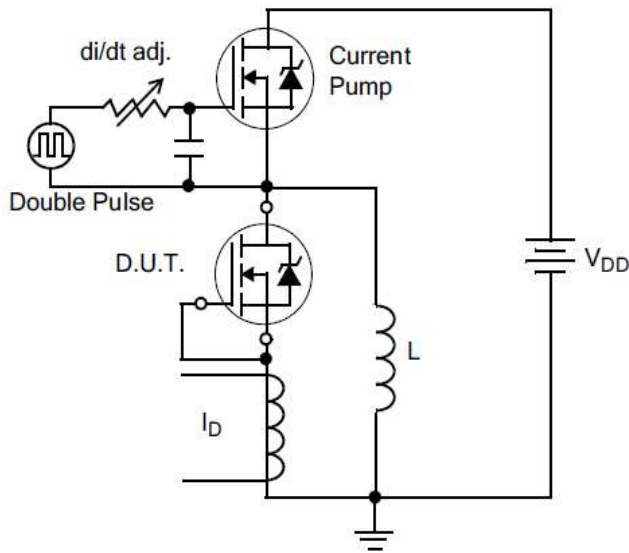


Figure16.Diode Reverse Recovery Test Circuit

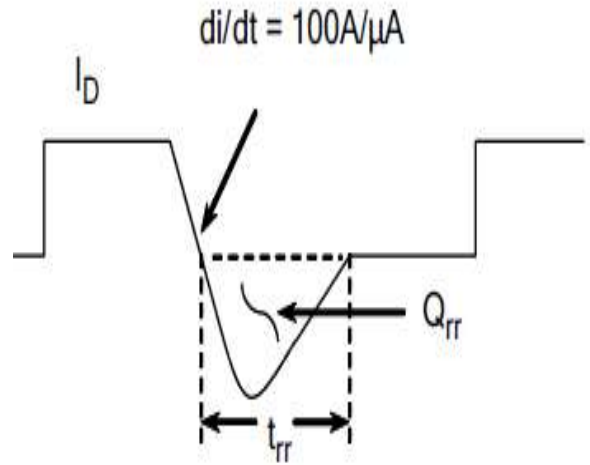


Figure17.Diode Reverse Recovery Waveform

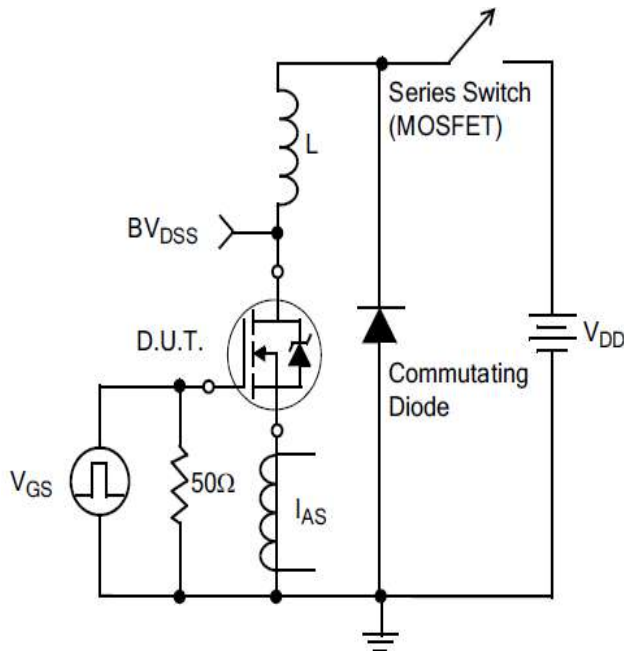
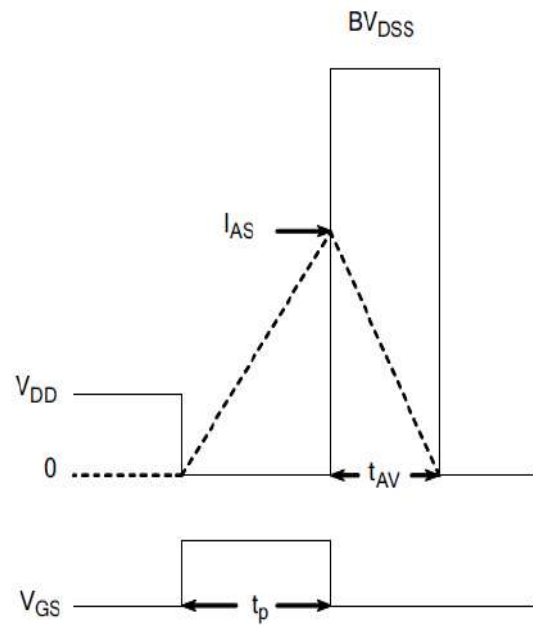


Figure18.Unclamped Inductive Switching Test Circuit

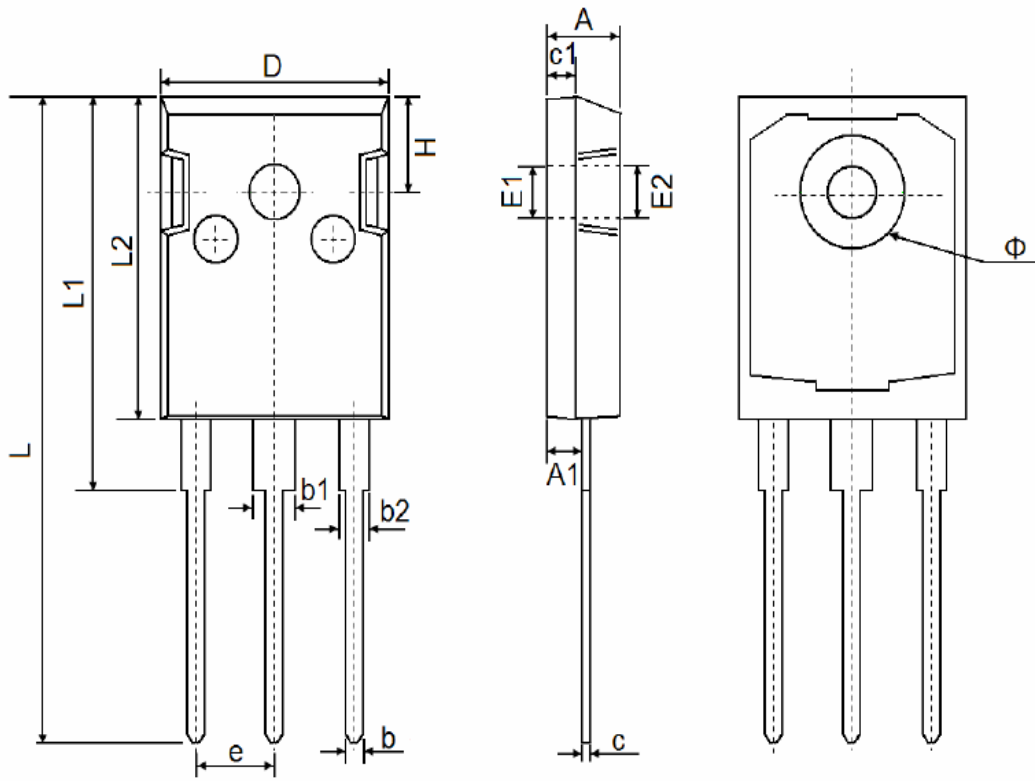


$$E_{AS} = \frac{I_{AS}^2 L}{2}$$

Figure19.Unclamped Inductive Switching Waveforms

## Package outline drawing

Unit:mm



## TO-247

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.850	5.150	0.191	0.200
A1	2.200	2.600	0.087	0.102
b	1.000	1.400	0.039	0.055
b1	2.800	3.200	0.110	0.126
b2	1.800	2.200	0.071	0.087
c	0.500	0.700	0.020	0.028
c1	1.900	2.100	0.075	0.083
D	15.450	15.750	0.608	0.620
E1	3.500 REF		0.138 REF	
E2	3.600 REF		0.142 REF	
L	40.900	41.300	1.610	1.626
L1	24.800	25.100	0.976	0.988
L2	20.300	20.600	0.799	0.811
Φ	7.100	7.300	0.280	0.287
e	5.450 TYP		0.215 TYP	
H	5.980 REF		0.235 REF	



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